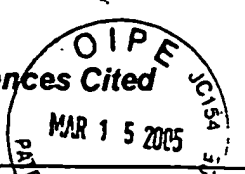


IDS considered.

Notice of References Cited 	Application/Control No. 10/091,787	Applicant(s)/Patent Under Reexamination SESHADRI ET AL.	
	Examiner Viet Q Nguyen	Art Unit 2840-2827	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,289,498	09-2001	Dupenloup, Guy	716/18
*	B	US-6,292,931	09-2001	Dupenloup, Guy	716/18
*	C	US-6,298,472	10-2001	Phillips et al.	716/18
*	D	US-6,295,636	09-2001	Dupenloup, Guy	716/18
*	E	US-6,463,560	10-2002	Bhawmik et al.	714/733
*	F	US-5,831,868	11-1998	Beausang et al.	716/18
*	G	US-5,903,466	05-1999	Beausang et al.	716/18
*	H	US-6,298,472	10-2001	Phillips et al.	716/18
*	I	US-6,378,123	04-2002	Dupenloup, Guy	716/18
*	J	US-6,421,818	07-2002	Dupenloup et al.	716/18
*	K	US-6,539,523	03-2003	Narain et al.	716/5
*	L	US-6,598,209	07-2003	Sokolov, Serguei A.	716/4
*	M	US-6,609,229	08-2003	Ly et al.	716/4

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP408153126A	06-1996	Japan	Oshika	G06F 17/50
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

V. Nguyen

Date 4/12/05